



Update on the LGFCS SOFC Technology and SECA Program

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Gerry Agnew and Rich Goettler

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LG Fuel Cell Systems Inc.

- **A group of LG companies (Corp, Electronics, & Chemical) acquired 51% ownership of Rolls-Royce Fuel Cell Systems Inc. (June 2012)**
- **The business focus remains on the commercialization of a “megawatt-scale” natural gas fueled fuel cell power system for stationary power generation**
- **The business will have its primary activities in Canton, Ohio with continued support from the team in Derby, England and a new team of resources based in Seoul, Korea.**
- **The business will leverage and benefit from expertise and capabilities from both LG Group and RR Group**

LG Fuel Cell Systems Inc.

- **LG and R-R are investing in the next phase of the business aimed at the development and testing of an integrated-system demonstrator, then transitioning to a commercial business with products and services**
- **A program of work has been planned which is aimed at designing, developing, and testing a prototype system in a “string-test”**
- **The “string-test” fuel cell power system will...**
 - **be at a smaller scale than 1MW, but include a product architecture capable of ‘scaling’ to ~1MW**
 - **Gas in to Grid Power out**
- **New Co-CEO alongside Mark Fleiner:**
 - **Dr In Jae Chung**



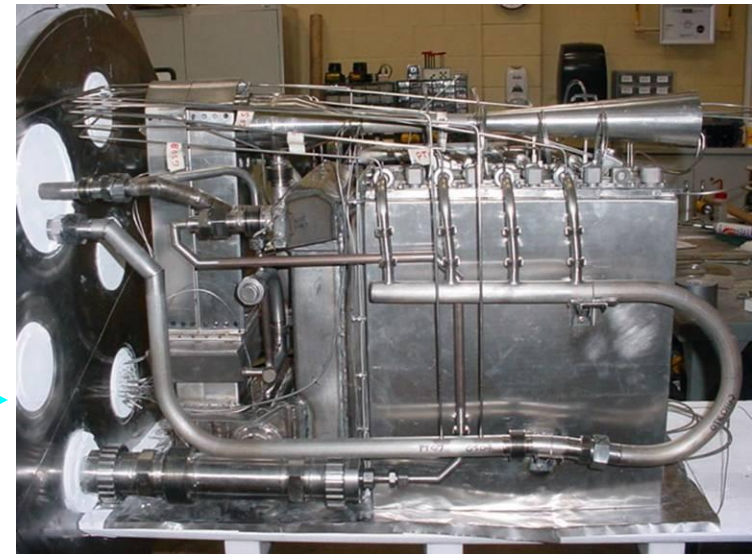
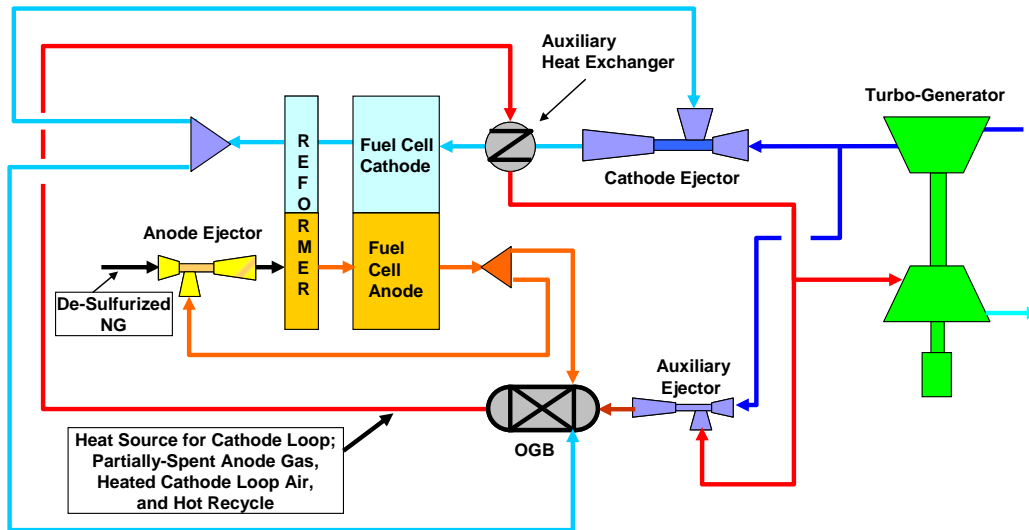
Outline

- **System Relevant Block-Scale Testing**
- **Cell Technology Status:**
 - Long-term durability
 - Degradation mechanisms and electrode optimization
- **Reliability Methodology**

Plant Configurations Similar for NG and IGFC

LGFCs NG “Dry Cycle” Configuration
Same configuration for an IGFC cycle

- Block metric testing matches full system cycle, components (less TG), operation and boundary conditions



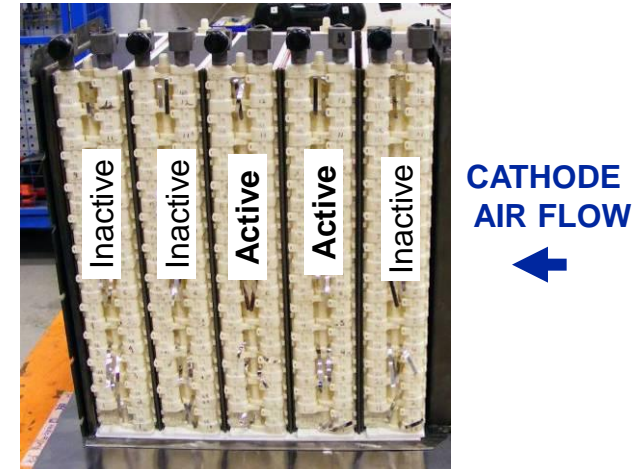
- Anode and cathode ejectors
- Reformers and heat exchangers
- Off-gas burners
- Insulation
- System control methodology

Phase 1 Metric Test (5,000 hours)

Operating Conditions:

- 2 active/3 inactive strips
- Cathode Conditions

Time	Pressure	Block Inlet Temp.	O ₂	H ₂ O
0-300 hrs	6.4 Bar	830C	14.1%	4.2%
>300 hrs			16.0%	3.0%

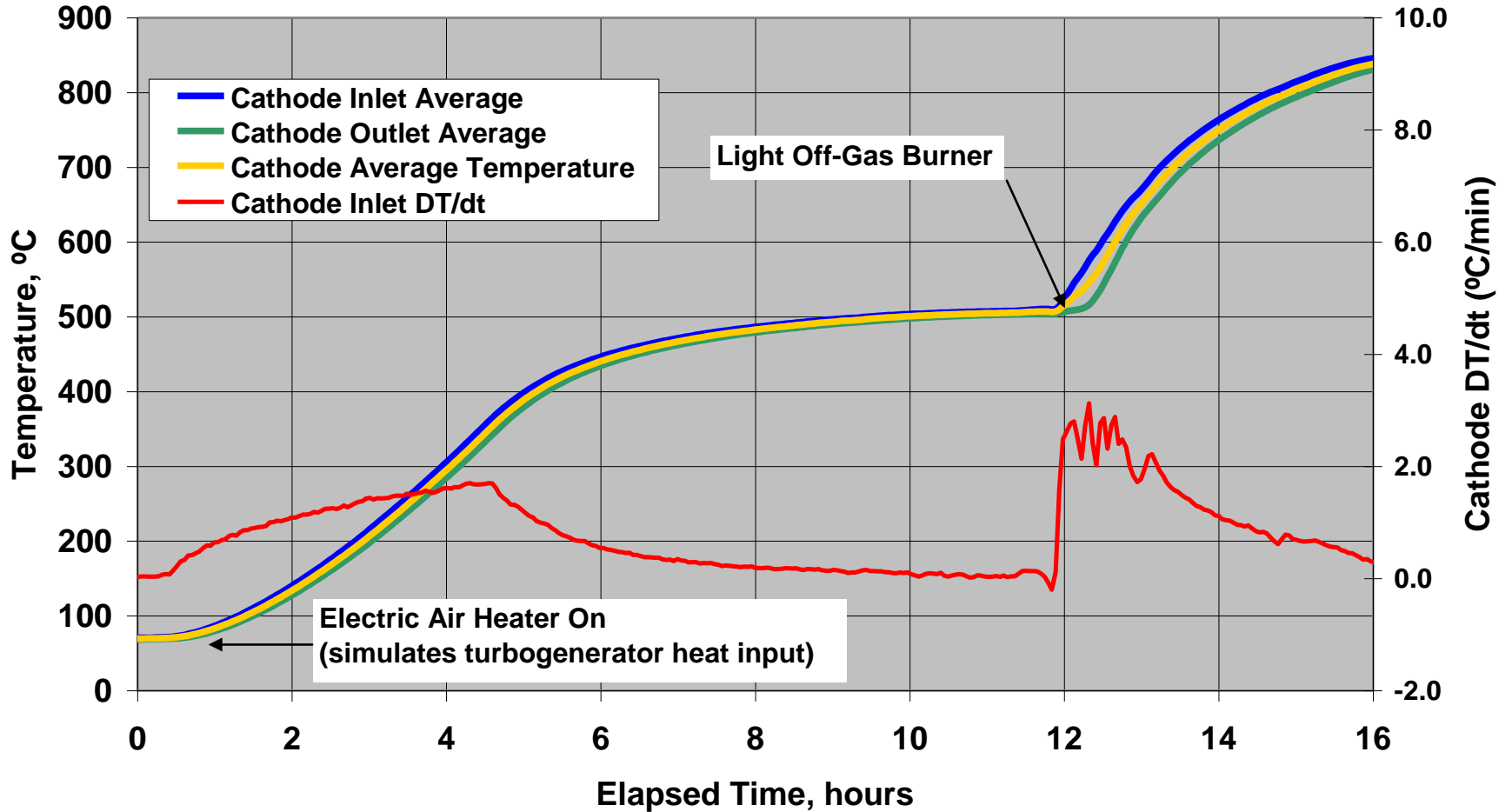


- Anode Conditions
 - Canton rig single pass, no anode recycle
 - Inlet composition matches that with recycle

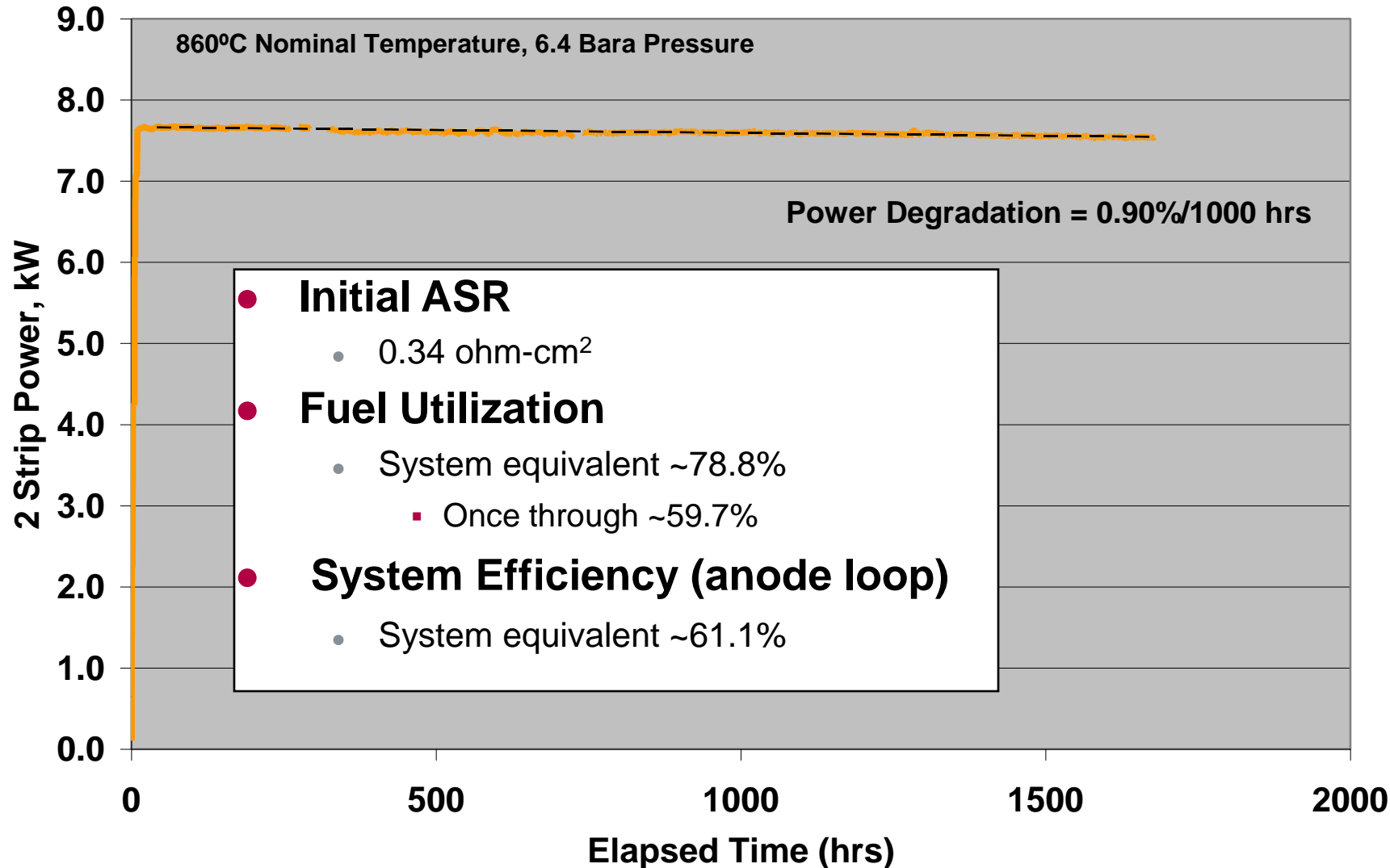
Time	Fuel Feed	H ₂	CO	CO ₂	CH ₄	N ₂	H ₂ O	S
0-300 hrs	H ₂ +CO ₂ (RWGS)	43%	18%	10%	2%	3%	24%	na
>300 hrs	pipeline NG, H ₂ O, O ₂ , CO ₂ (Oxy-CPOX)	41%	17%	11%	1%	9%	21%	~35 ppbv



Block start-up similar to full system operation



Phase 1 Test – Performance and Durability ⁸



Phase 2 Metric Test (3,000 hours)

- **Test rig in Derby, UK more closely matches the system configuration:**
 - anode recycle loop
 - implements primary and auxiliary cathode recycle loops
- **Phase 2 test used bottled CH₄**
- **Status:**
 - 5 strips built and pre-reduced
 - Early-Sept start date



Pre-reduction of Strips

- Planned for high volume manufacturing QA
- Now being implemented for block-scale testing



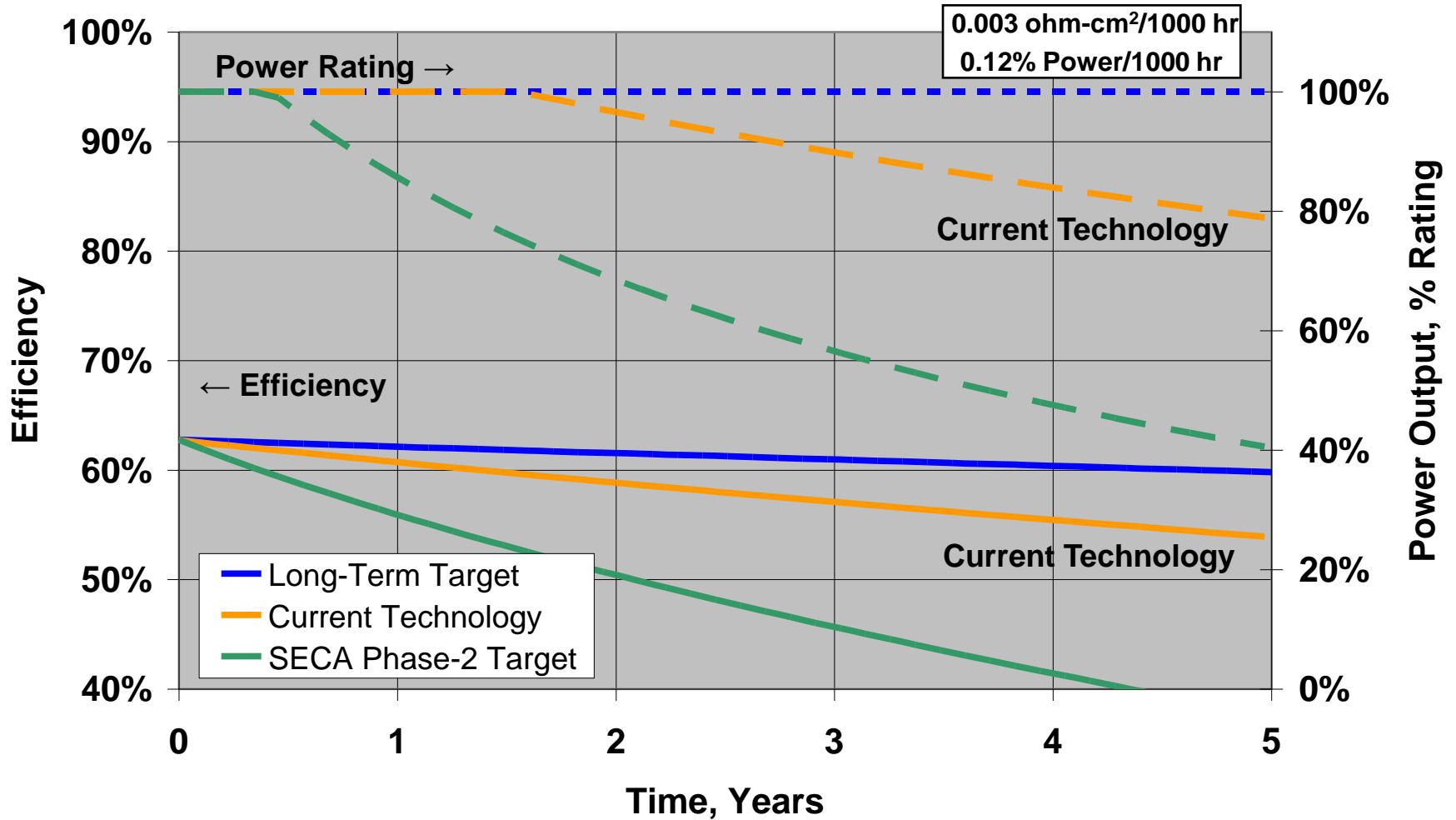
Bundle OCV					
Bundle	Strip 1	Strip 2	Strip 3	Strip 4	Strip 5
1	358	352	352	353	354
2	355	349	349	350	350
3	356	349	349	350	352
4	352	347	347	346	350
5	351	348	348	348	350
6	351	347	347	348	349
7	353	348	348	348	350
8	354	349	349	349	351
9	355	350	350	349	352
10	355	351	351	349	351
11	354	352	352	350	353
12	353	354	354	353	355

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Degradation and Life in Operation

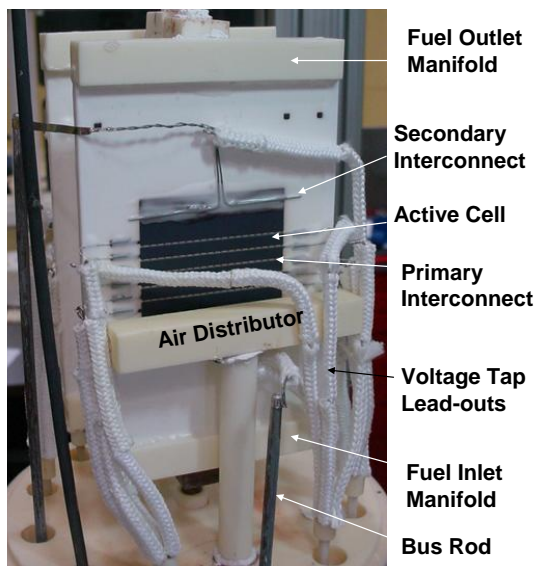
- Degrade efficiency to meet constant power



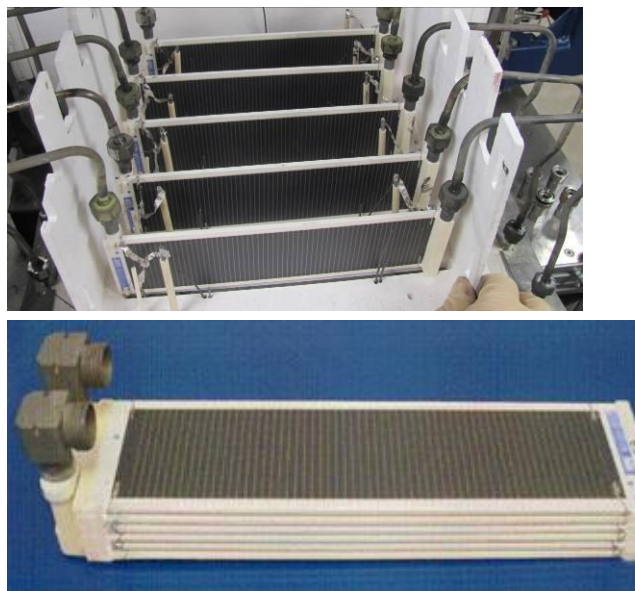
Durability Testing Approach Builds up from Subscale Testing

- Map performance and durability over operating envelope
- Confirm at larger scales while improving manufacturing consistency

Atmospheric Stands – Technology Screening
Pressurized Stands – Full System Testing

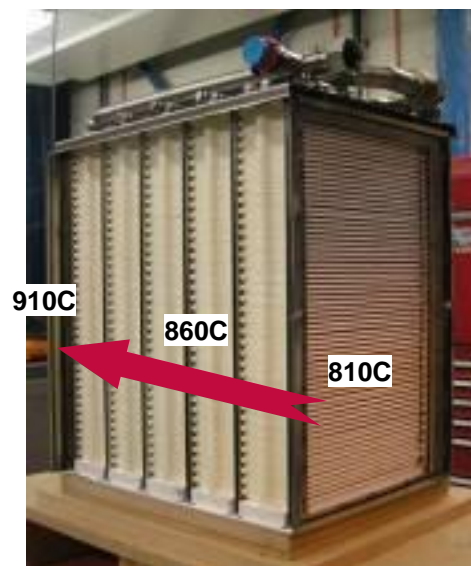


Provides Detailed Cell Component Analysis



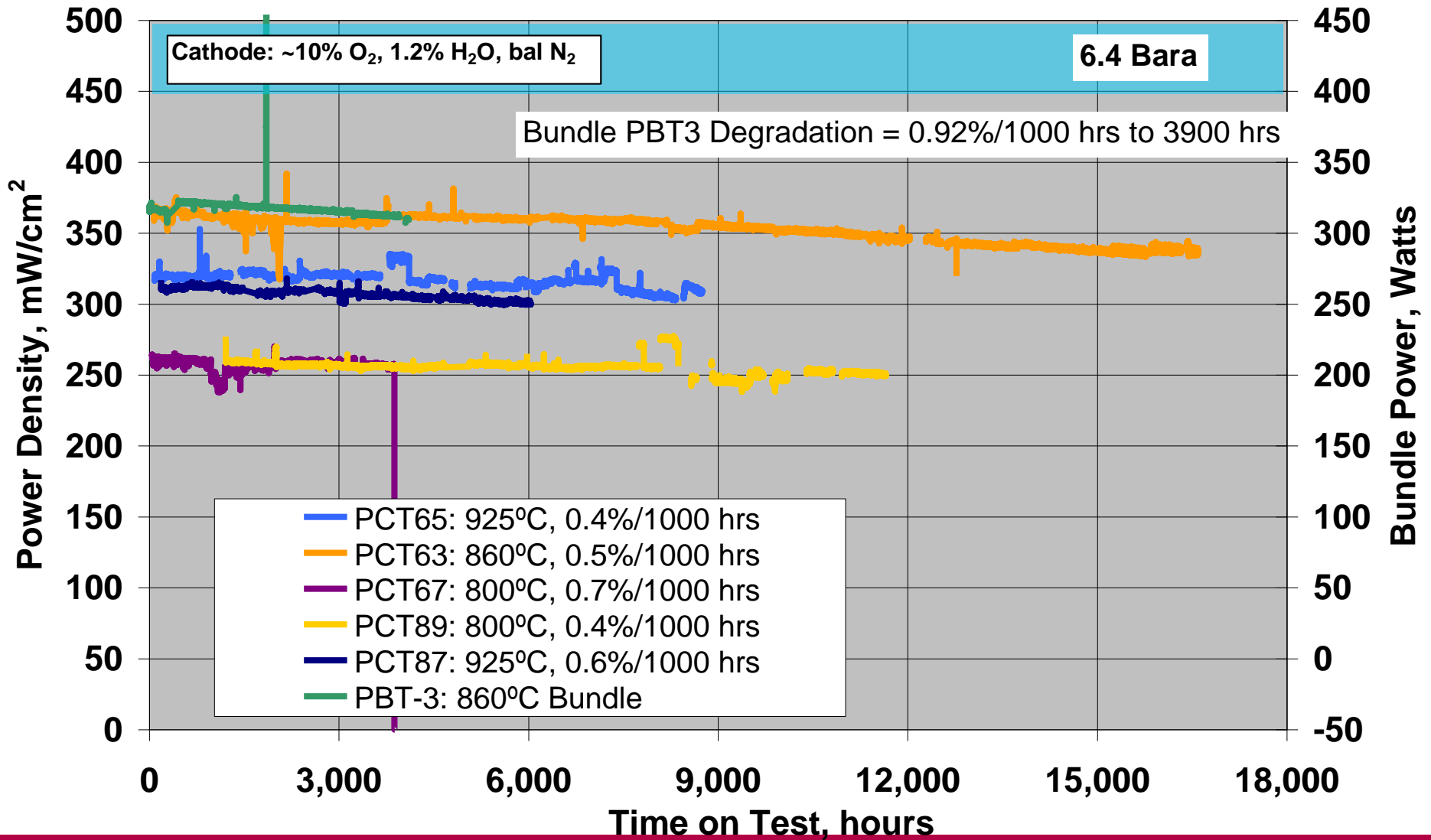
Prototypic Tube Manufacture
Tube-Level Performance

Fully Prototypic Environment
Including BOP Components

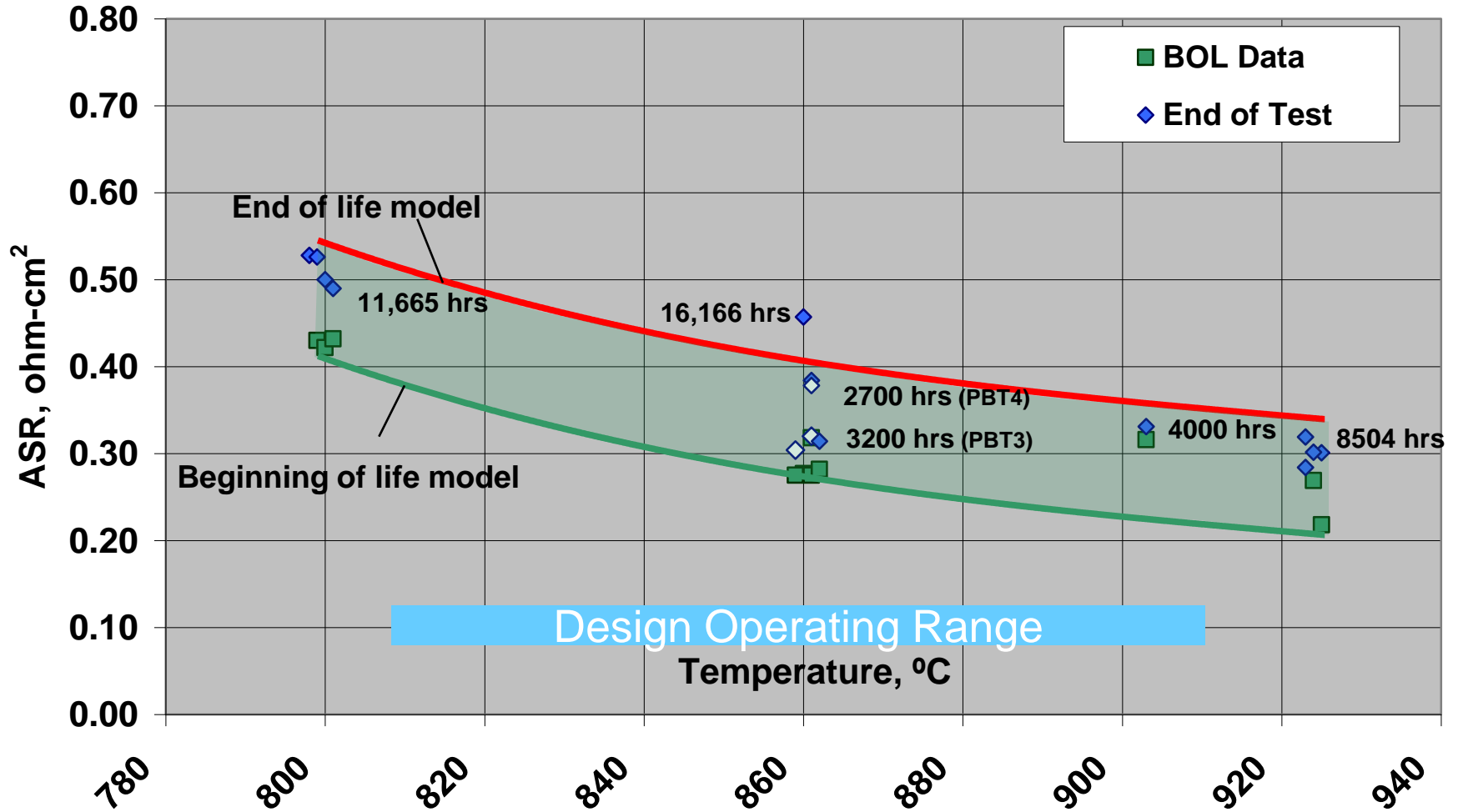


Full Prototypic Scale

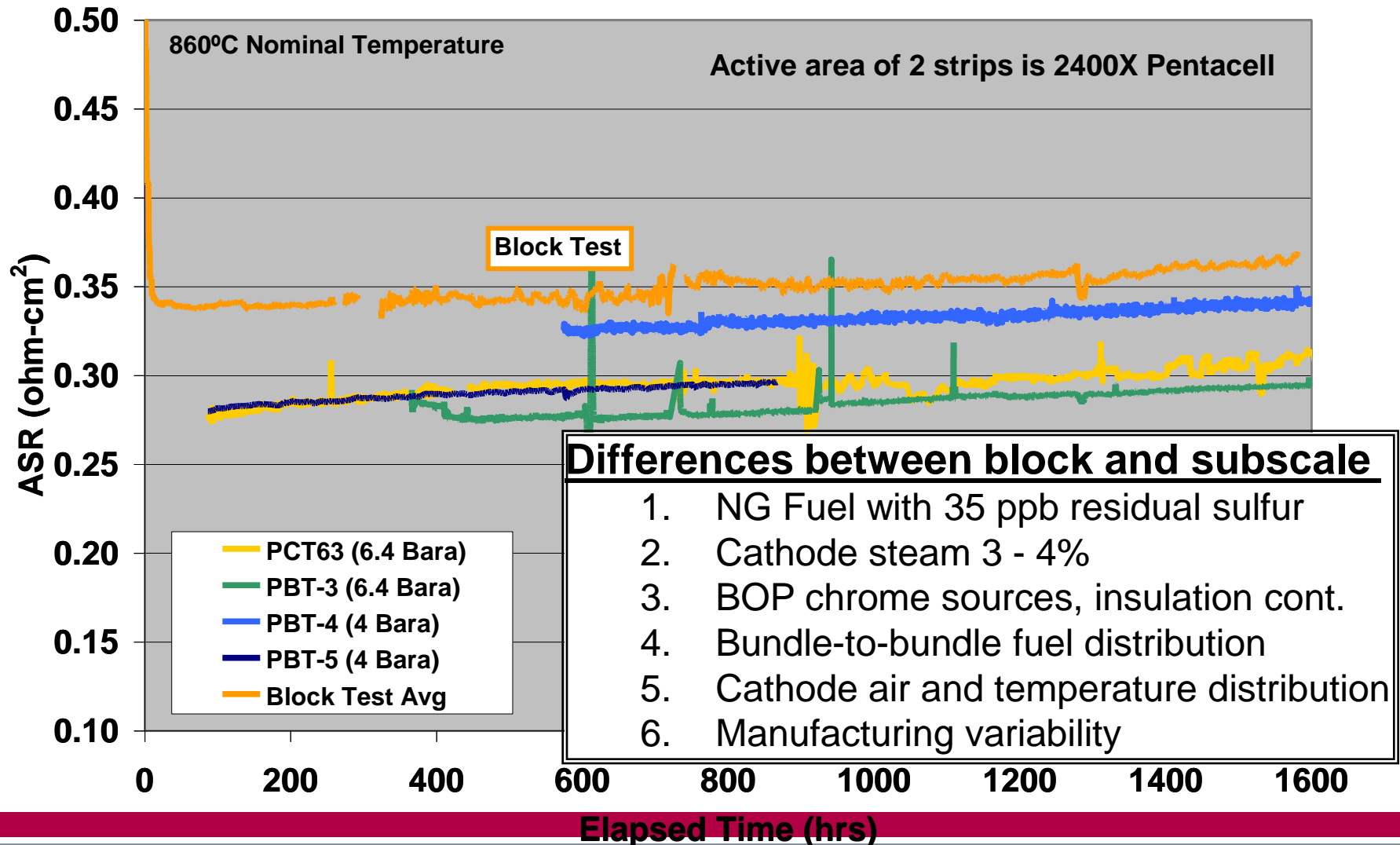
Long-Term Degradation < 1%/1000 hours



Subscale Durability Map Demonstrates Durability Trends



Scale-up of durability demonstrated, some variation in performance

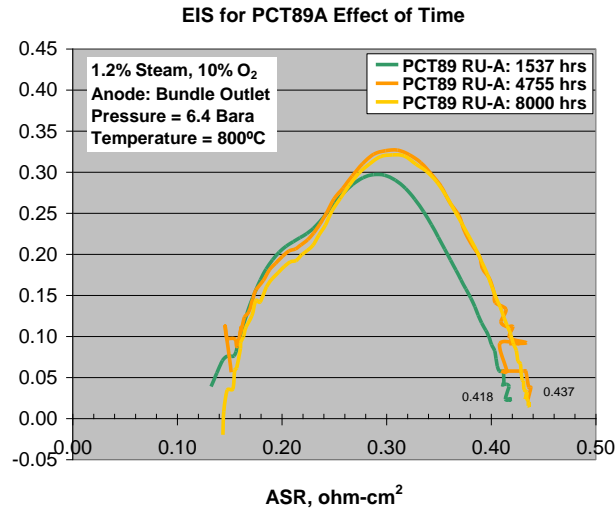


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- **Cell Technology Status:**
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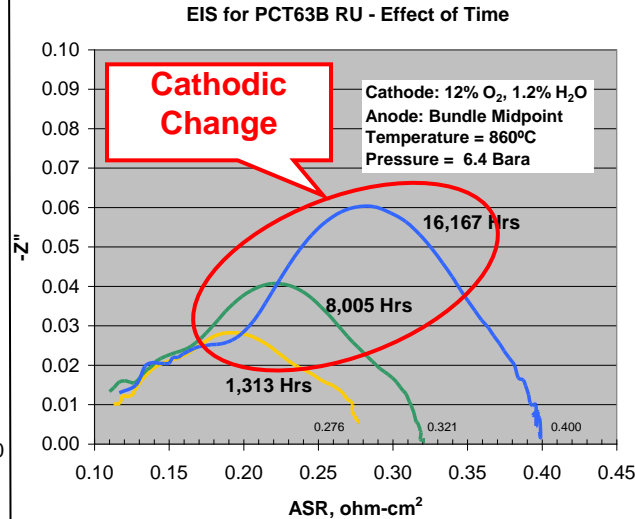
Key Degradation Contributions Identified: Anode and Cathode Polarization Resistance

Low-Temperature (800°C)
Initial Cathode degradation
then stability



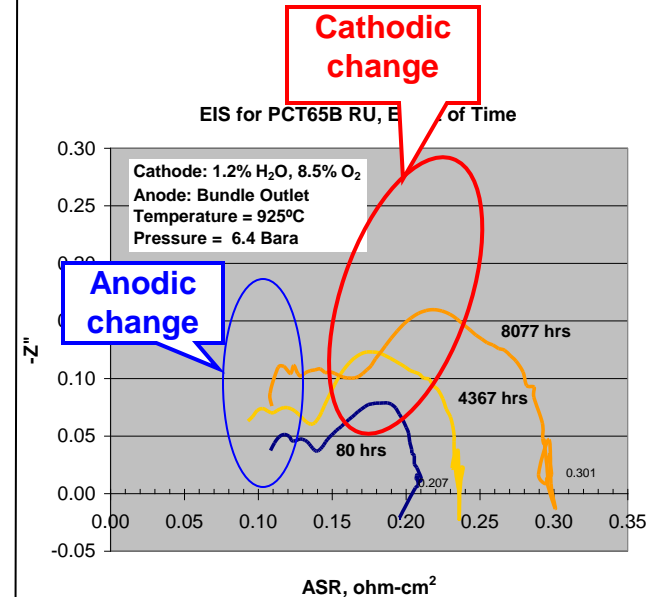
**Overall Degradation Rate:
0.0038 ohm-cm²/1000 hrs**

Mid-Temperature (860°C)
Cathode degradation is
dominant



**Overall Degradation Rate:
0.0083 ohm-cm²/1000 hrs**

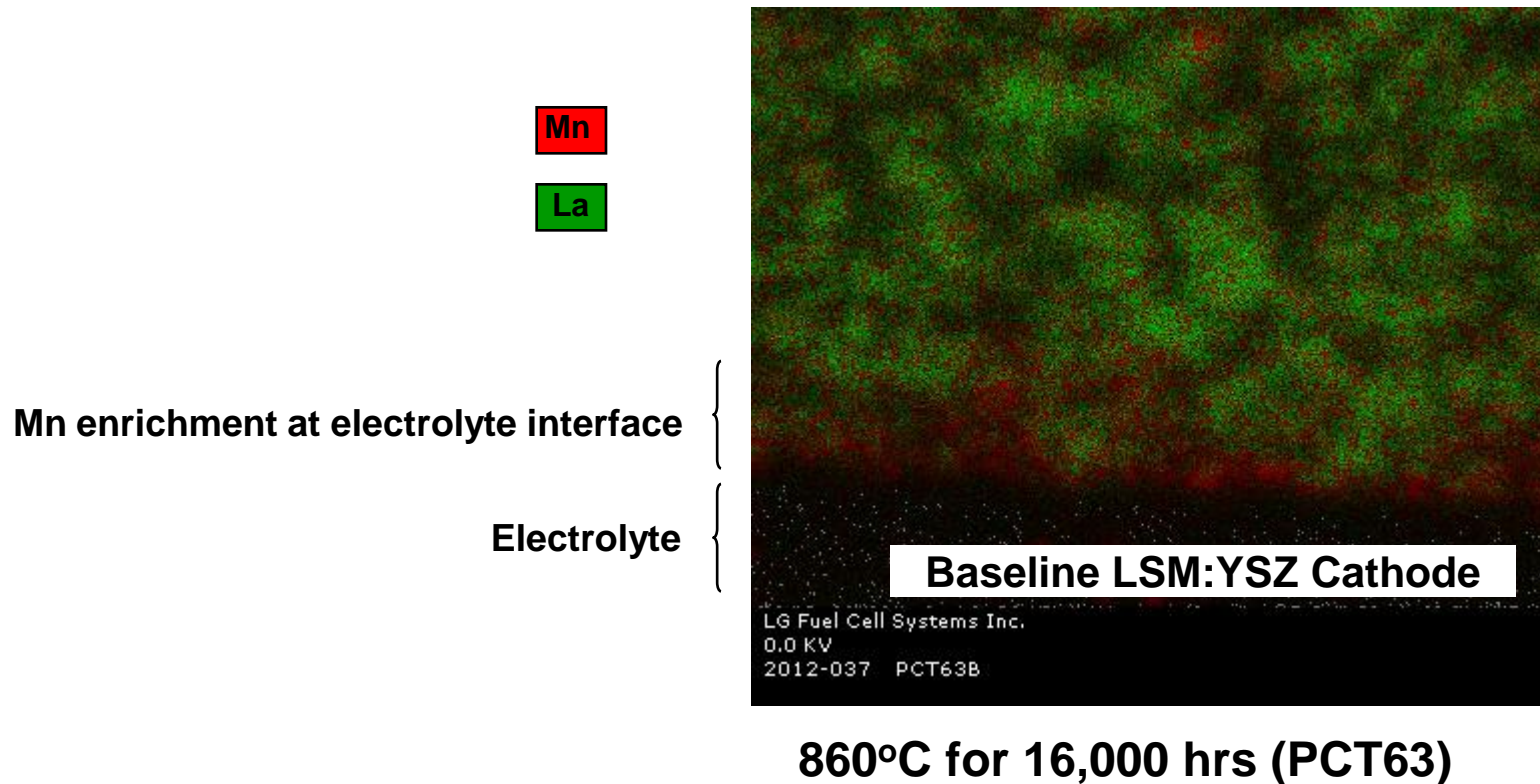
High-Temperature (925°C)
Anode + Cathode
degradation observed



**Overall Degradation Rate:
0.0120 ohm-cm²/1000 hrs**

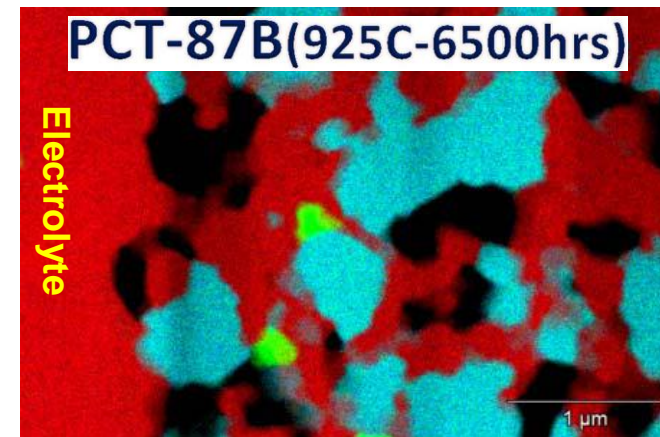
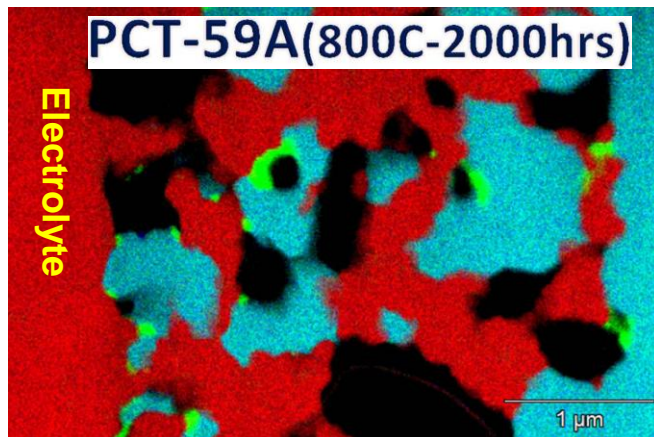
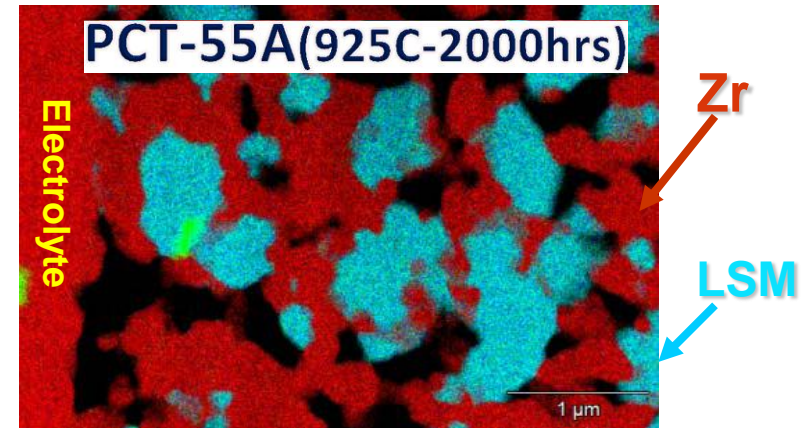
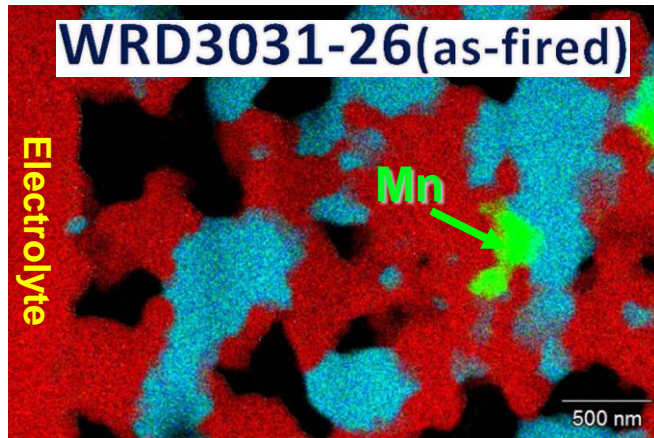
Cathode Changes Observed Long-Term

- Mn-rich at cathode/electrolyte interface
- Some cathode densification showing up at 16,000 hours, relatively absent at 8,000 hours (for testing at 860C)



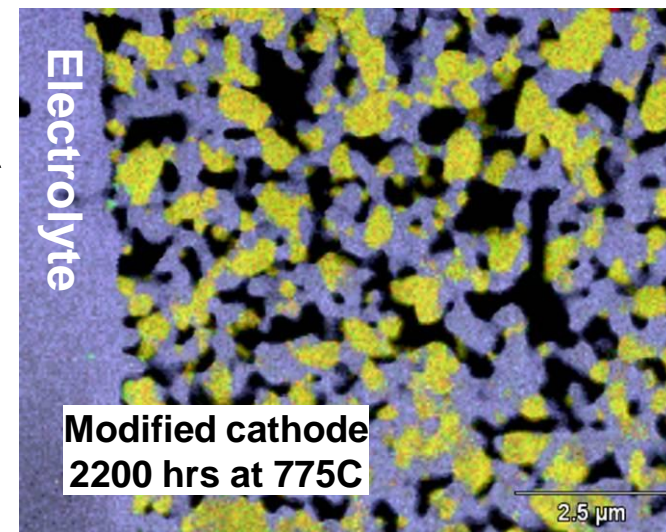
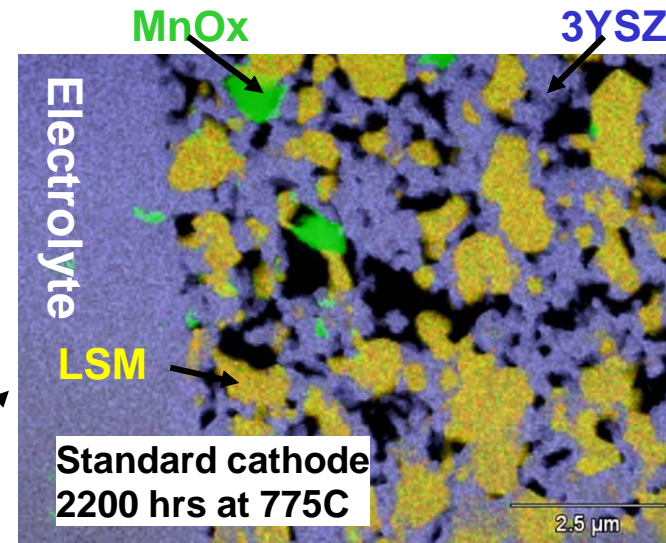
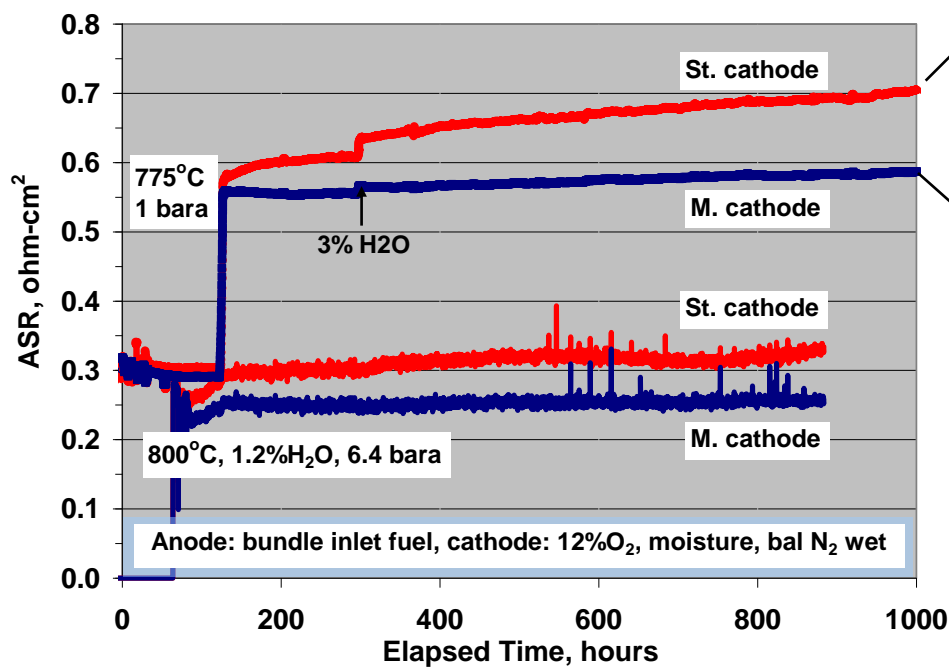
Exploring MnO_x presence vs. operating temp.

- Free MnO_x observed in both as-fabricated and tested cells
- Initial analysis: more smaller MnO_x grains observed at TPB for cell tested at lower temperatures



Improved Cathode – Promising Results at Low Temperatures

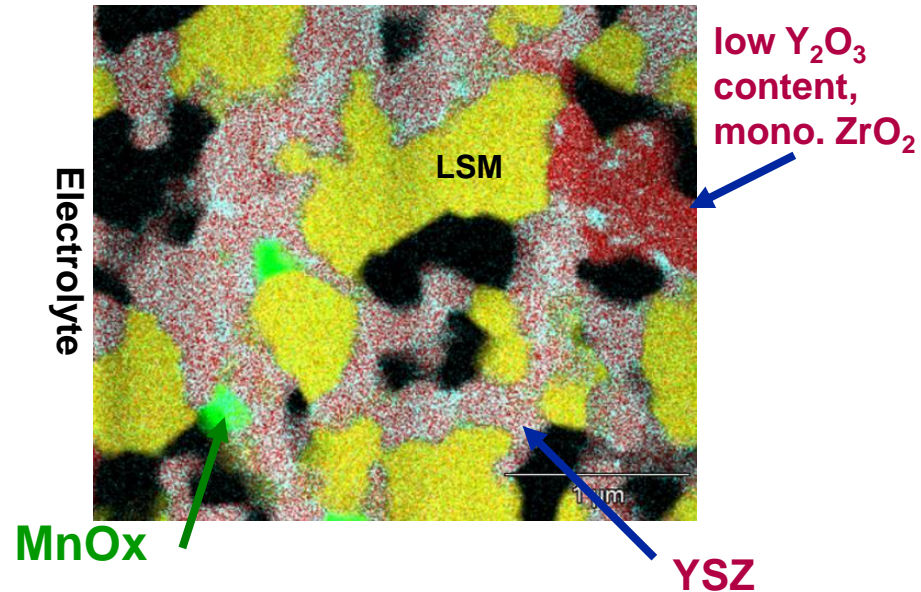
- Lower degradation rate than standard cathode at low-temperature operation
- Free MnO_x segregation from LSM may cause performance loss



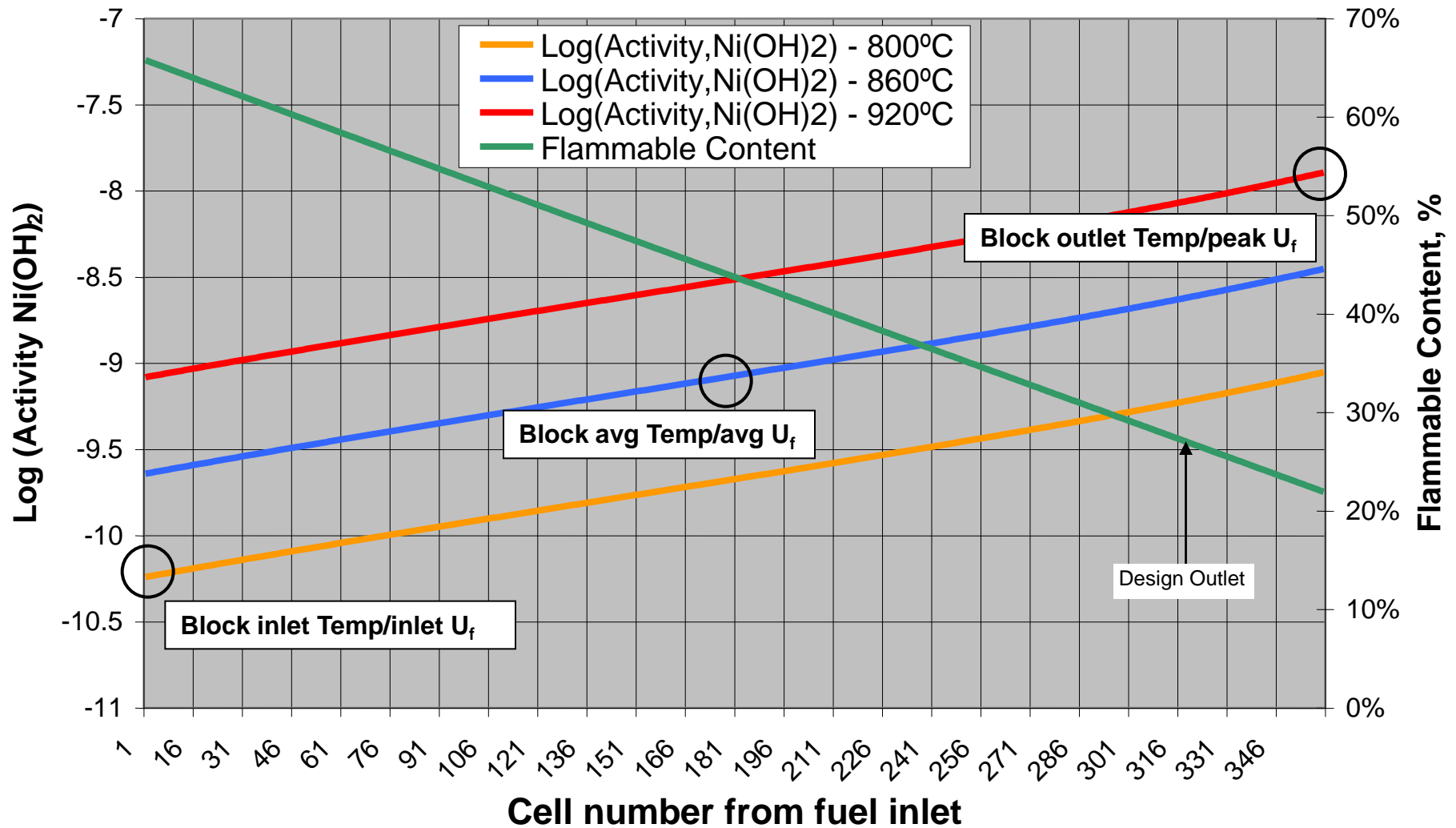
Standard Cathode Shows Segregation of Stabilizing Ion from Ionic Phase

- YSZ is stable after short period of operation at both low and high temperature operation
- Local Y depletion was detected after 6500 hrs of operation at 925°C leading to monoclinic ZrO_2
- Modified LSM cathode shows no evidence of monoclinic ZrO_2

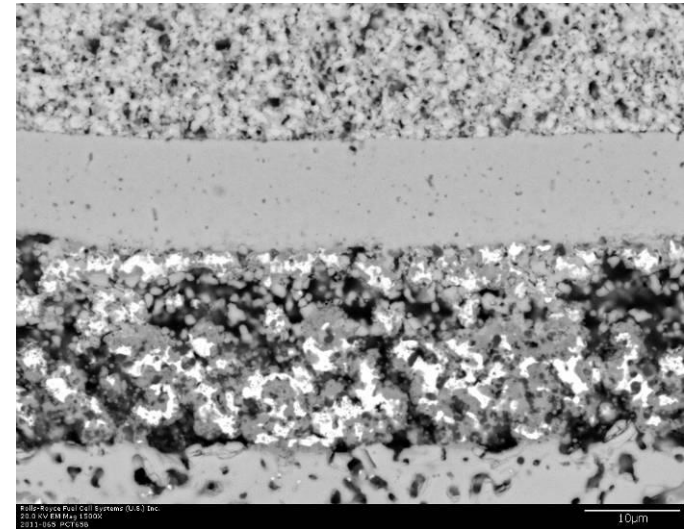
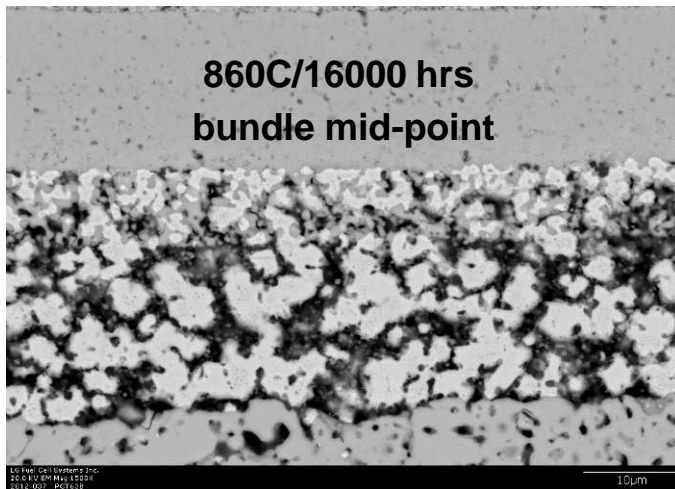
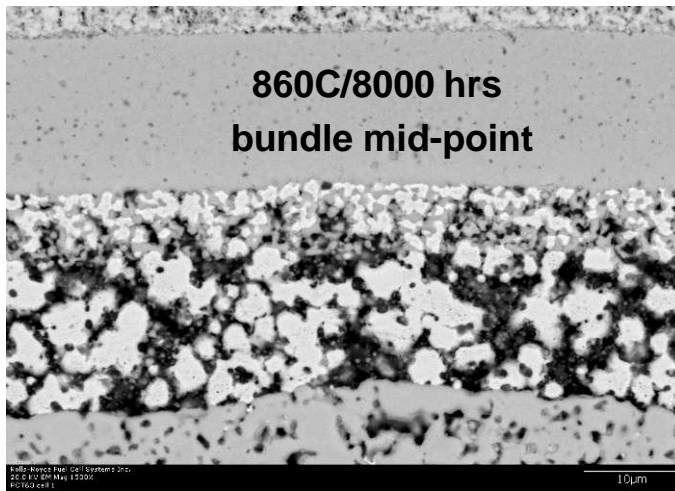
Standard cathode at 925°C for 6500 hrs



Ni(OH)₂ Equilibrium within Blocks



Anode microstructure changes greatest at extremes of temperature and U_f

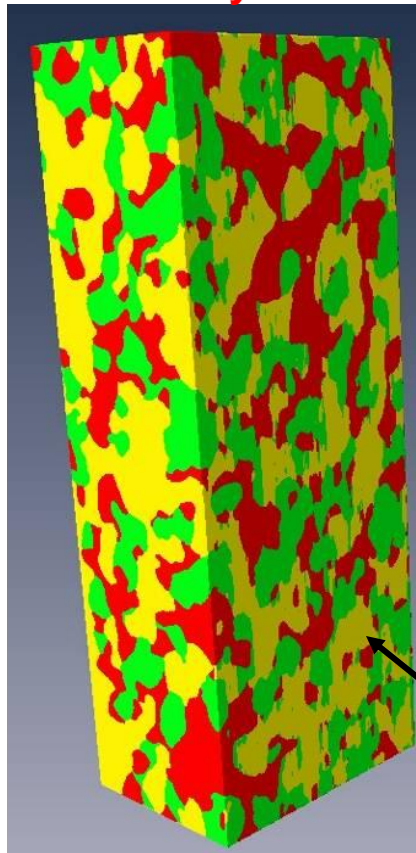


Aggressive testing outside block envelope

Anode 3D Reconstruction Highlights Changes at Anode/ACC Interface



Porosity=29%

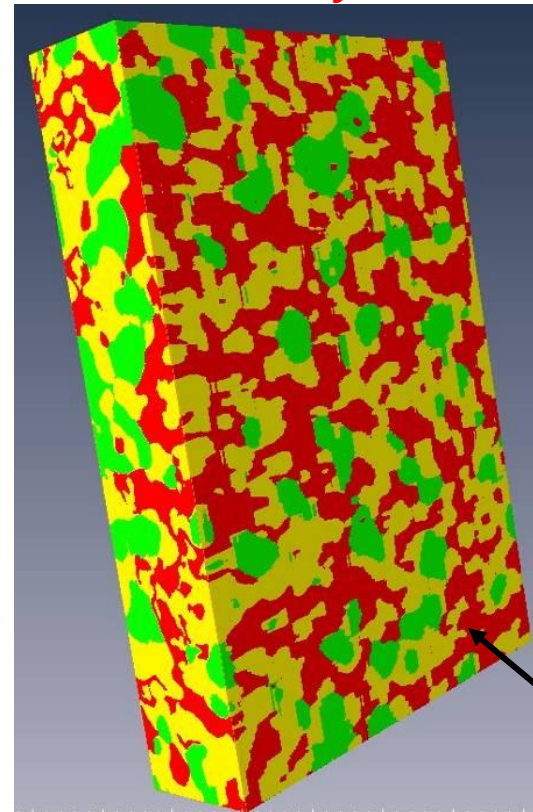


As-reduced anode

3D pillar was constructed By FIB milling of series of thin slices

Surface close to Anode/ ACC Interface

Porosity=41%



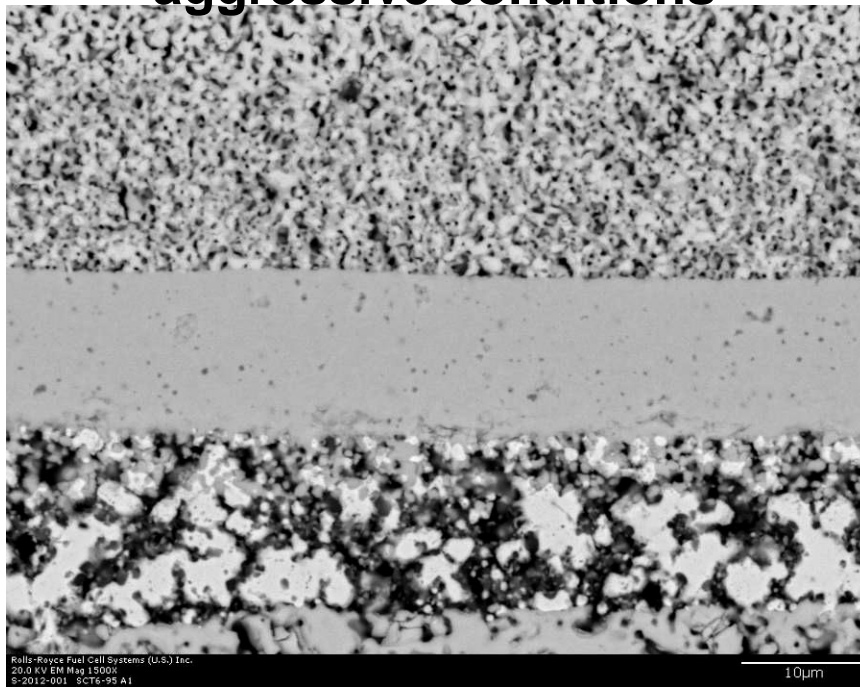
Aggressively tested anode



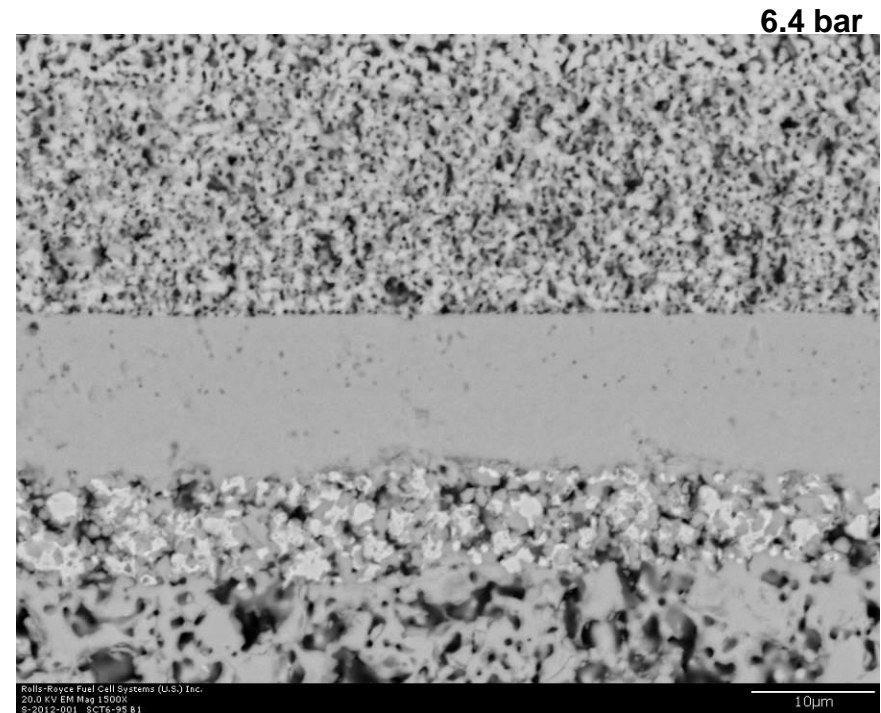
Surface close to Anode/ACC Interface

Single Layer Anode Technology Showing Improved Microstructure Stability

- Two single cells were tested in same rig under aggressive temperature and fuel utilization conditions
- Post test analysis performed after 630 hrs of testing at aggressive conditions



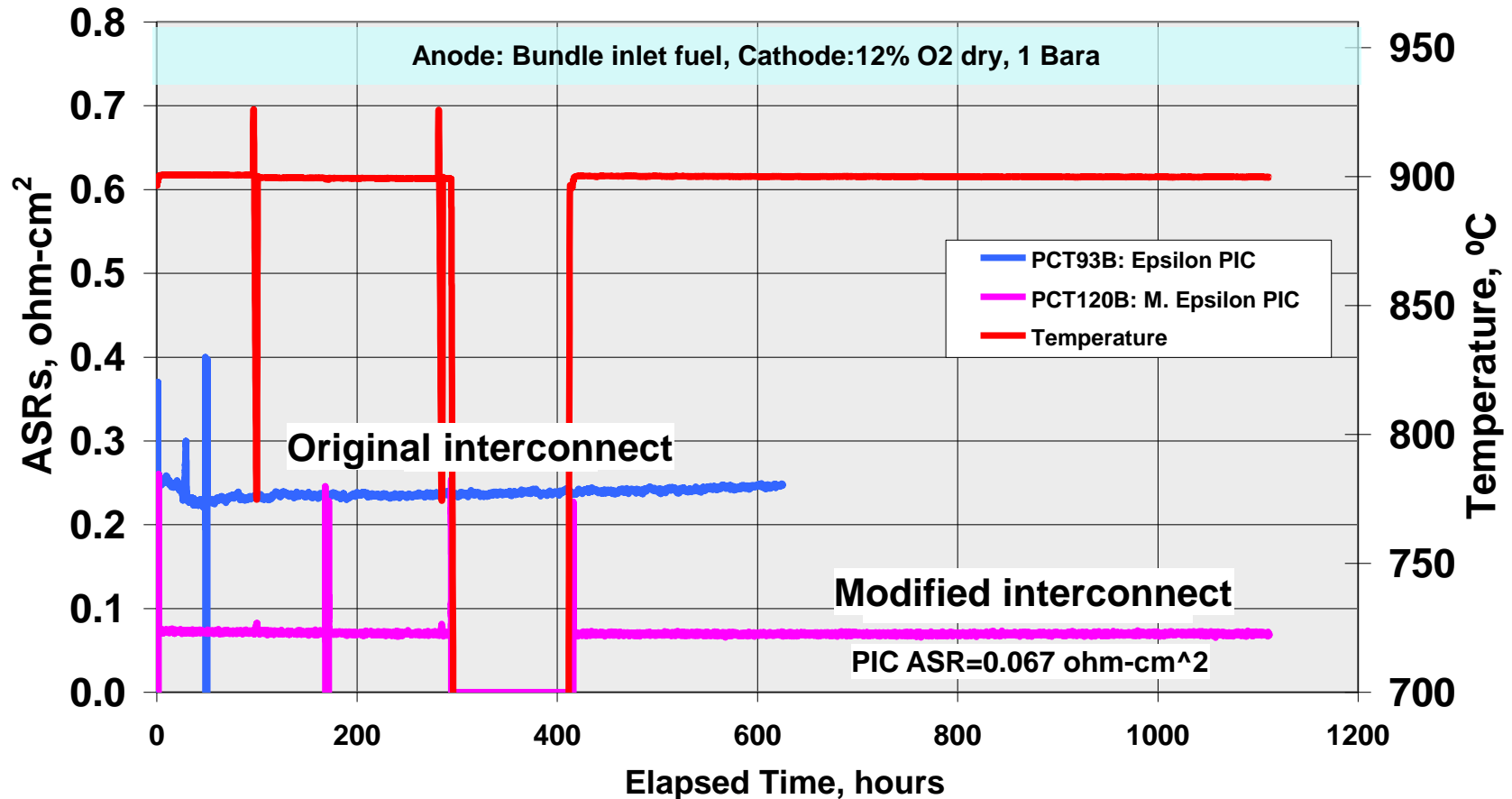
SCT6-95A: Standard anode



SCT6-95B: Single layer anode

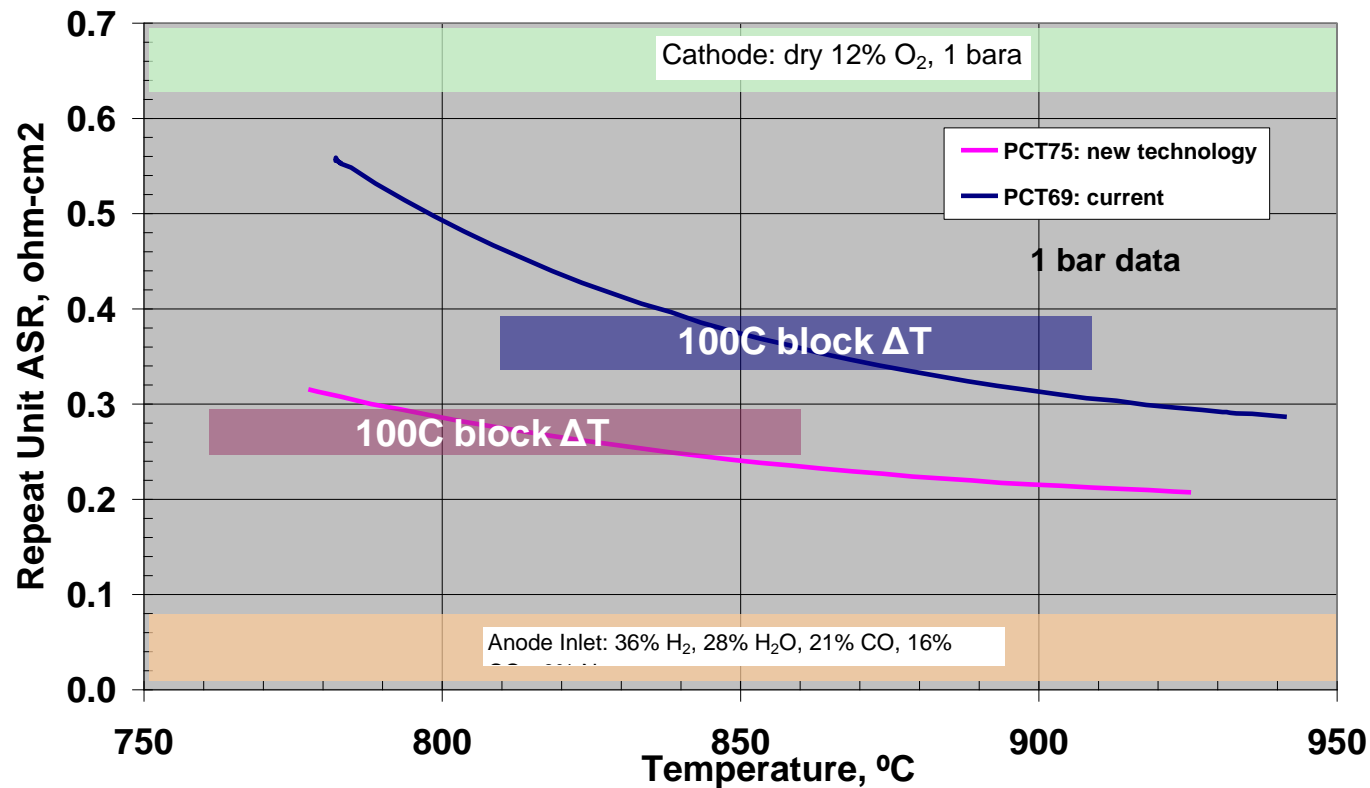
A New Cell-to-Cell Interconnection Materials Set ²⁷ Developed for Single Layer Anode Technology

- Interconnect ASR >0.2 ohm-cm² from materials incompatibility issue with anode
- Optimized formulation achieved typical 0.07 ohm-cm² range of ASR



Focus on reducing peak operating temperature to extend lifetimes

- Latest cell technology offers potential for lower degradation rates and improved system efficiency
- Lower ASR cell technology is entering full system durability screening

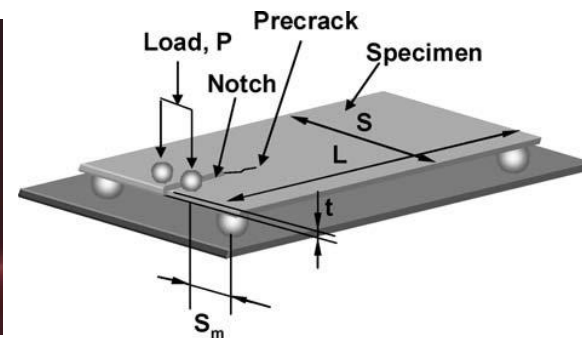
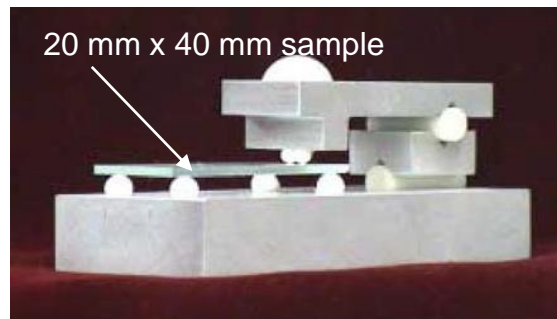
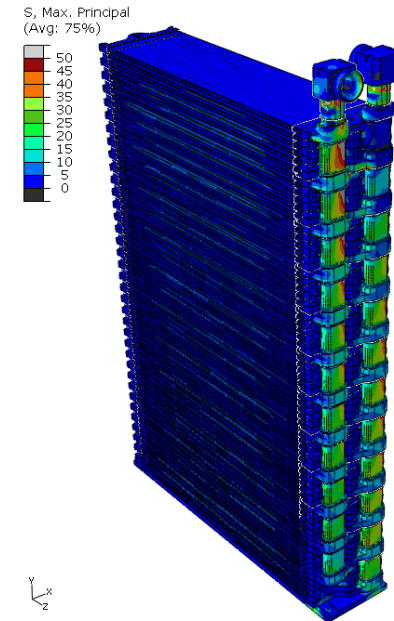


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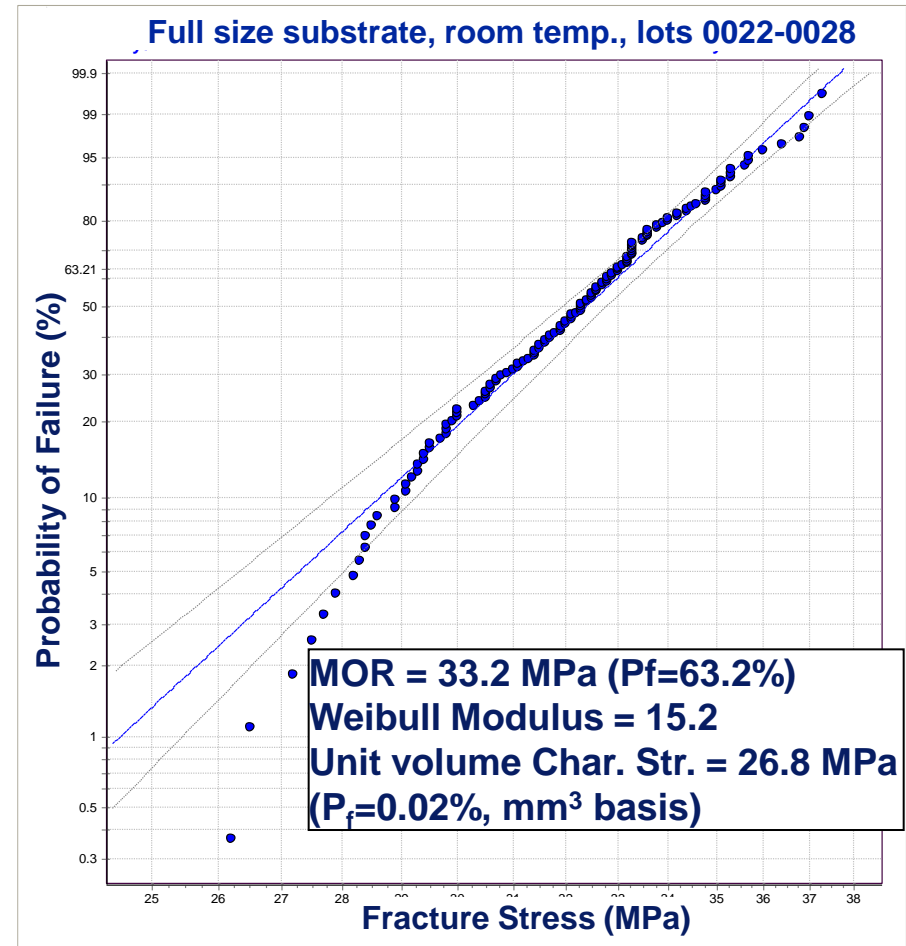
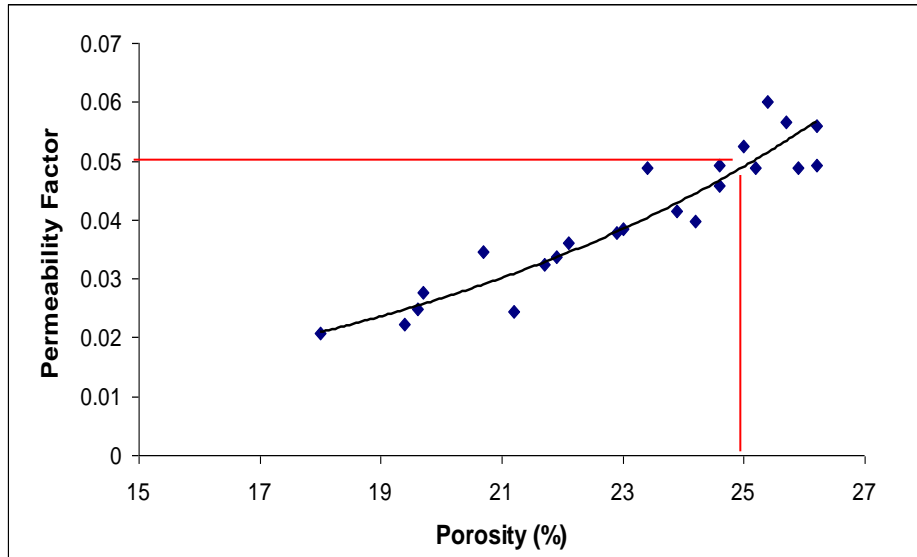
Infant Mortality and Time Dependent Reliability Considerations

- **Infant Mortality:**
 - Thermal and stress analysis
 - Insure that design and system operational modes can accommodate the stack material
 - Material property database being generated
- **Life-time Reliability**
 - Time dependent, slow crack growth mechanisms being studied



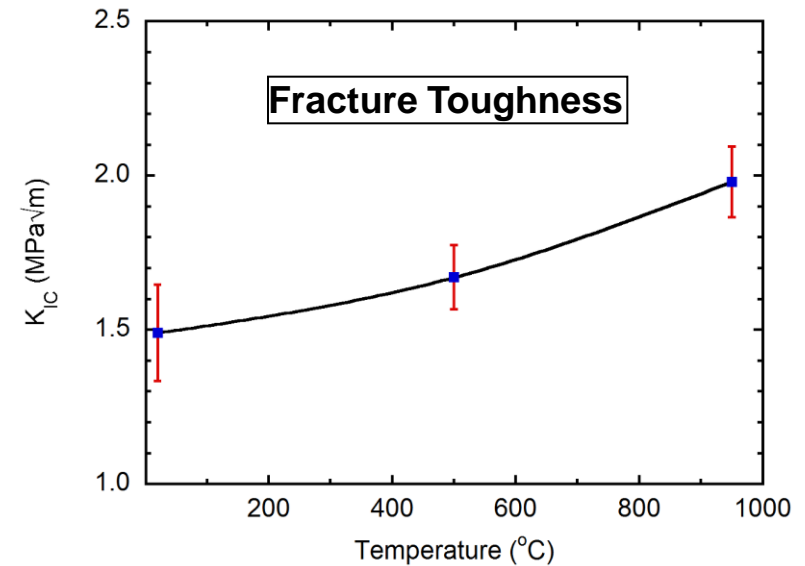
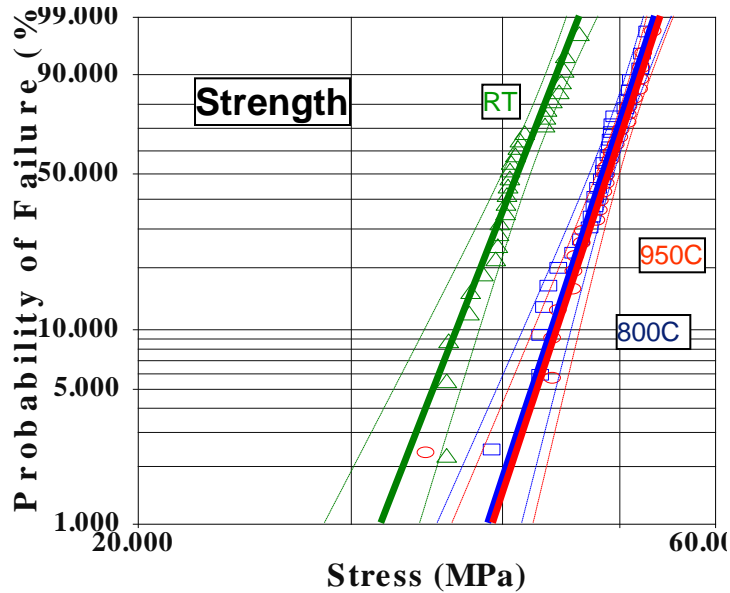
Strength specification met for higher porosity substrates

- Room temp. MOR >29 MPa (full-size substrate)
- Weibull modulus >10
- ~25% porosity for permeability factor spec. of 0.05 0.005



MMA Substrate Strength and Toughness Increase with Temperature

- Substrate is MgO+MgAl₂O₄ (MMA)
- Improved strength and toughness at temperature benefits reliability



Test coupons from substrate edges

Temperature	Strength, MPa (Pf=63.2%)	Weibull Modulus
room temp.	42.3	16.2
800C	49.5	19.3
950C	50	19.2

ORNL Performing Slow Crack Growth (SCG) Measurements of MMA Substrate

- Thus far the MMA substrate is demonstrating reasonable SCG resistance
- Data in fuel environments with moisture content is most relevant

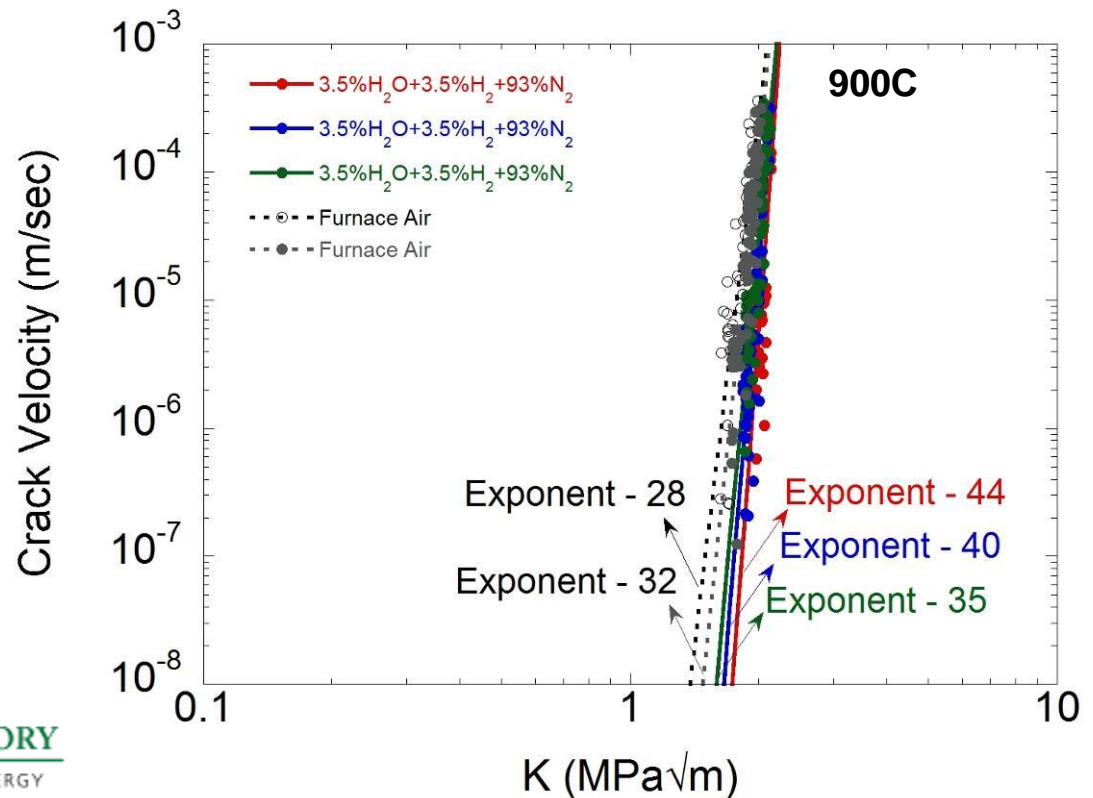
$$v = AK_I^n$$

v , crack velocity

K_I , stress intensity

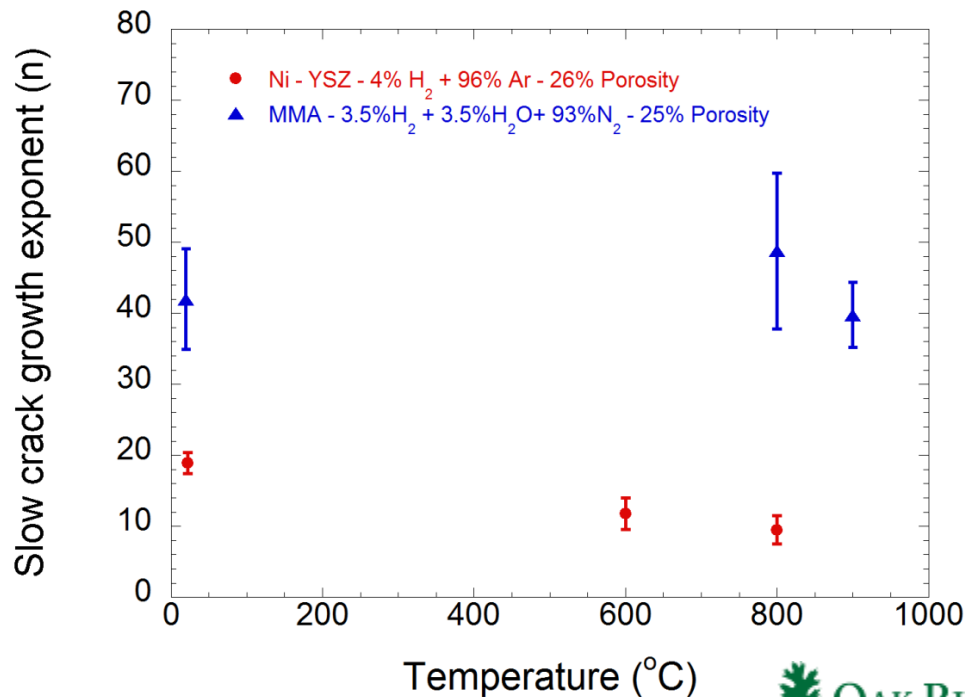
A and n , $f(\text{mat'l, environ.})$

n , slow crack growth exponent



SCG Comparison of MMA and Ni:YSZ

- ORNL had previously tested porous Ni:YSZ under Core Technology Program
- MMA substrate compares very favorably to other SOFC substrate materials
- Very limited SCG literature data for electrolytes (n from 8-25, air/900-1000C), none in high H₂O fuel
 - Compressive electrolyte residual stresses for anode- and MMA-supported may reduce risk. Electrolyte SCG a greater concern for electrolyte supported SOFC



SCG data combined with Weibull characteristics can allow lifetime predictions

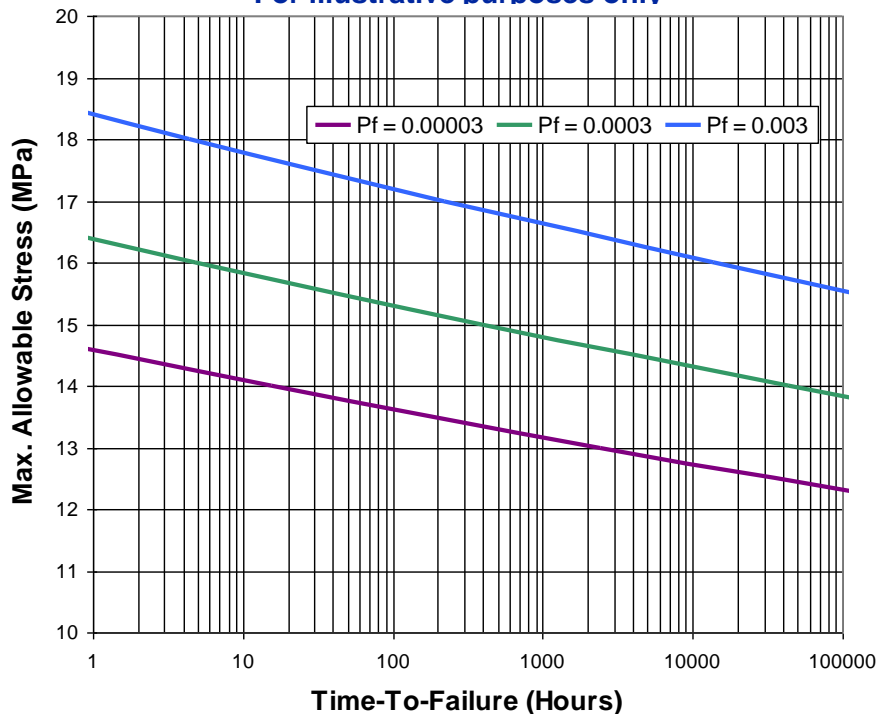
- Guides design allowable stresses for components to meet lifetimes (probabilistic)
- Consider P_f of 1 in 360 (0.003) for blocks (1 failed substrate within a 5 strip block)

Relationships developed originally for glass components (Weiderhorn)

$$K_{II} = K_{IC} \left(\frac{\sigma}{\sigma_o} \right) \left[\frac{-V_E}{\ln(1 - P_f)} \right]^{1/m}$$

$$t = \frac{2(K_{II}^{2-n} - K_{IC}^{2-n})}{(n-2)A\sigma^2 Y^2}$$

Example of calculations/predictions with SCG data.
For illustrative purposes only



Requires mat'l properties at operating condition:

K_{IC} , fracture toughness
 σ_o , characteristic Weibull strength
 m , Weibull modulus
 n , slow crack growth exponent
 A , slow crack growth coefficient

Requires inputs of:

Y , geometric factor for crack orientation/loading
 P_f , desired probability of failure for component
 V_E , Volume of mat'l in component under stress
 σ , stress level of elements within component

Conclusions

- **LGFCs established, combining LG and Rolls-Royce talents and resources to commercialize MW-scale IP-SOFC technology**
- **Stack degradation rates trending under the SECA Phase 2 target**
- **Next generation/optimized electrodes screened and entering long-term durability testing to advance to 5-year service life**
- **Current emphasis on ceramic materials database generation and stress analysis to progress understanding of reliability**

Acknowledgements

- **This material is based on work supported by the Dept. of Energy National Energy Technology Laboratory under Award Number DE-FE0000303**
- **LGFCs project manager Patcharin Burke and the entire SECA program management team**
- **UK and US based LGFCs team**
- **LGFCs SECA partners: ORNL, CWRU, Univ. of Conn. and Univ. S. Carolina**

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